



Integrated Device Technology, Inc.
6024 Silver Creek Valley Road, San Jose, CA - 95138

PRODUCT/PROCESS CHANGE NOTICE (PCN)

PCN #: TB1711-02 DATE: 22-Nov-2017 Product Affected: F159VNLGN, F159VNLGN8 Date Effective: 22-Feb-2018	MEANS OF DISTINGUISHING CHANGED DEVICES: <input type="checkbox"/> Product Mark <input type="checkbox"/> Back Mark Traceability to the test location is <input type="checkbox"/> Date Code maintained by IDT and available on <input checked="" type="checkbox"/> Other request
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Contact: IDT PCN DESK E-mail: pcndesk@idt.com	Attachment: <input checked="" type="checkbox"/> Yes <input type="checkbox"/> No Samples: Please contact your local sales representative for sample request.
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DESCRIPTION AND PURPOSE OF CHANGE:

<input type="checkbox"/> Die Technology <input type="checkbox"/> Wafer Fabrication Process <input type="checkbox"/> Assembly Process <input type="checkbox"/> Equipment <input type="checkbox"/> Material <input type="checkbox"/> Testing <input checked="" type="checkbox"/> Manufacturing Site <input type="checkbox"/> Data Sheet <input type="checkbox"/> Other	<p>This notification is to advise our customers that IDT is adding Giga Solution, Taiwan as an alternate facility for Test process for the selective products that are presently tested at IDT Penang, Malaysia facility.</p> <p>Attachment I details the change.</p>
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RELIABILITY/QUALIFICATION SUMMARY:

There is no expected change to the product quality or reliability performance. Please refer to Attachment I for Electrical correlation data.

CUSTOMER ACKNOWLEDGMENT OF RECEIPT:

IDT records indicate that you require written notification of this change. Please use the acknowledgement below or E-Mail to grant approval or request additional information. If IDT does not receive acknowledgement within 30 days of this notice it will be assumed that this change is acceptable.

IDT reserves the right to ship either version manufactured after the process change effective date until the inventory on the earlier version has been depleted.

Customer: _____	<input type="checkbox"/> <i>Approval for shipments prior to effective date.</i>
Name/Date: _____	E-Mail Address: _____
Title: _____	Phone# /Fax# : _____

CUSTOMER COMMENTS: _____

IDT ACKNOWLEDGMENT OF RECEIPT:

RECD. BY: _____ DATE: _____



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PCN Type: Manufacturing Site - Alternate Test Location
Data Sheet Change: None
Detail Of Change:

This notification is to advise our customers that IDT is adding Giga Solution, Taiwan as an alternate facility for Test process for the selective products that are presently tested at IDT Penang, Malaysia facility.

This change will allow IDT the flexibility to ship from either facility and will provide the increased capacity, flexibility and shorter lead time to meet market demand.

There is no change in the Test processing flows. Load boards and test programs are the same at both qualified facilities. IDT has completed the electrical test correlation and based on the test results we do not anticipate any impact on device performance. The testing is fully compatible and transferrable between the test facilities with no change to the test coverage.

There is no change in the moisture sensitivity level (MSL).

If you require samples to conduct evaluations, please contact your local sales representative to acknowledge this PCN and request samples.



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Qualification Information and Qualification Data:

Electrical Test Correlation Results

Vehicle: F159VNLGN

Sample size: 528 electrically good units tested by handler &
10 good and 10 reject units tested by hand test

Description	Existing Test (IDT - IDT, Penang)	Alternate Test (Giga Solution, Taiwan)
Tester Platform	LTX	LTX
Test Program	IDTF159V_ZK_CB_SEQ0200	IDTF159V_ZK_CB_SEQ0200
Test Site	Single Site	Single Site
Test Temperature	Ambient	Ambient
Test Correlation Results	100%	100%
Number of Good Units Correlated (Handler)	528 pcs	528 pcs
528 units Bin 1 run	Passed	Passed
528 units Bin 1 datalog correlation	Passed	Passed
Number of Good Units (Hand Tested)	10 pcs	10 pcs
10 good units datalog correlation	Passed	Passed
Number of Reject Units (Hand Tested)	10 pcs	10 pcs
10 reject units datalog correlation	Passed	Passed